

Application/Control No.	Applicant(s)Patent under Reexamination BODIN, UIF	
09/926,280		
Examiner	Art Unit	
Lina Vann	2005	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST, IEEE, GOOGLE	8/22/2005	LY		
Consulted Steven Nguyen	8/24/2005	LΥ		
combine text search with classification	8/24/2005	LY		
Search IEEE	(115/06	g		
East Search	7/14/65	d		
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